**Indian Institute of Technology Palakkad**
भारतीयप्रौद्योगिकीसंस्थानपालक्काड
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**16-02-2026**

## CORRIGENDUM-I

**Tender No. TENDER/2025-26/445**

**Date of Publication: 02-02-2026**

**Date/Time of Closing: 17-02-2026, 15:00 hours**

Indian Institute of Technology Palakkad Invites TENDER under Two-bid system for the:

**SUPPLY, INSTALLATION,TESTING AND COMMISSIONING OF ATOMIC FORCE MICROSCOPY FACILITY**

**It is hereby conveyed that the Closing Date and Time for the submission of Bids for the Tender cited in the reference have been extended till 24-02-2026, 15.00 hours**

**The updated technical specifications is appended herewith for reference.**

**REGISTRAR**
**IIT PALAKKAD**

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Date: 2026.02.16 16:56:25 IST

## Amendments in Technical Specifications

| Sl No | Reference | Existing specifications in the tender | Amendments |
|---|---|---|---|
| 1 | **2. Atomic Force Microscope for Material Science applications**<br>1. Major features | In order to support transmission illumination, fluorescence, confocal laser scanning microscopy, and other advanced optical techniques such as TIRF, STED, Raman etc, the AFM should be able to be mounted on an inverted light microscope (IOM) of popular brands. | This is to be removed |
| 2 | **2. Atomic Force Microscope for Material Science applications**<br>2. Modes of Operation | Other modes, which come as default modes with the offered instrument should also be mentioned. Following optional modes should be available for future upgradation | Other modes, which come as default and optional modes with the offered instrument such as Standard MFM with amplitude/frequency modes, PFM, Non-contact mode, glove box compatibility etc. should also be mentioned. Optional modes/modules can be mentioned in a separate section with their advantages and specifications to procure it according to the budget or later for future upgradation.<br><br>Other preferred modes for reference (Should quote separately)<br>- Fast scanning module (upto 90 Hz)<br>- Scanning Capacitance Microscopy (SCM)<br>- DFRT and Contact Resonance for PFM applications<br>- Scanning Thermal Microscopy (SThM)<br>- Nano thermal analysis<br>- Scanning Spreading Resistance Microscopy (SSRM)<br>- Sample Temperature Control system with wide range of temperature (-35℃ to 250℃) and dedicated |

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|---|---|---|---|
| | | | heater element<br>- Dynamic Mechanical Analysis module |
| 3 | **2. Atomic Force Microscope for Material Science applications**<br><br>2. Modes of Operation | Cryostage measurements should be available with a temperature range from -120℃ to 220℃ or better | Cryostage measurements should be available with a temperature range from -35℃ to 250℃ or better |
| 4 | **2. Atomic Force Microscope for Material Science applications**<br><br>3. Scanner type and parameters | XY axes scanning range: ≥100 um | XY axes scanning range: ≥90 um |
| 5 | **2. Atomic Force Microscope for Material Science applications**<br><br>3. Scanner type and parameters | Z-axis scanning range: ≥15 um for both open and closed loop | Z-axis scanning range: ≥10 um for both open and closed loop |
| 6 | **2. Atomic Force Microscope for Material Science applications**<br><br>3. Scanner type and parameters | IR low-coherence light source with vertical incidence and it should be controlled through the software. All scanner specifications must be demonstrated in the lab after installation | IR low-coherence light source/Red laser with vertical incidence and it should be controlled through the software. All scanner specifications must be demonstrated in the lab after installation |
| 7 | **2. Atomic Force Travel range of the stage:**<br><br>**4.** Stage and sample dimensions | Travel range of the stage: ≥20 x 20 mm | Travel range of the stage: ≥150 x 150 mm |
| 8 | **2. Atomic Force Microscope for Material Science applications**<br><br>7. Software | Automated sample tilt correction with the 3 stepper motors for tip scanning heads | This is to be removed |